# INTERNATIONAL STANDARD

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# Filters using waveguide type dielectric resonators –

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IEC 61337-1:2004

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#### INTERNATIONAL ELECTROTECHNICAL COMMISSION

# FILTERS USING WAVEGUIDE TYPE DIELECTRIC RESONATORS –

# Part 1: Generic specification

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International Standard IEC 61337-1 has been prepared by IEC technical committee 49: Piezoelectric and dielectric devices for frequency control and selection.

This part of IEC 61337 cancels and replaces IEC 61337-1-1:1995 and IEC 61337-1-2:1999.

The text of this standard is based on the following documents:

FDIS	Report on voting
49/685/FDIS	49/695/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

IEc 61337 consists of the following parts, under the general title *Filters using waveguide type dielectric resonators*:

Part 1: Generic specification

Part 2: Guidance for use

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual edition of this generic specification may be issued at a later date.

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# FILTERS USING WAVEGUIDE TYPE DIELECTRIC RESONATORS –

## Part 1: Generic specification

#### 1 General

### 1.1 Scope

This part of IEC 61337 applies to filters using waveguide type dielectric resonators of assessed quality using either capability approval or qualification approval procedures. It also lists the test and measurement procedures which may be selected for use in detail specifications for such filters.

#### **1.2** Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), Letter symbols to be used in electrical technology

IEC 60050(561):1991, International Electrotechnical Vocabulary (IEV) – Chapter 561: Piezoelectric devices for frequency control and selection

IEC 60068-1:1988, Environmental testing – Part 1: General and guidance

IEC 60068-2-1:1990, Environmental testing - Part 2: Tests - Test A: Cold

Ittps://standards.iteh.al/eatalog/standards/iec/0005ede9-fd8a-43e6-a523-77ebd0ada683/iec-61337-1-2004 IEC 60068-2-2:1974, Environmental testing – Part 2: Tests – Test B: Dry Heat

IEC 60068-2-6:1995, Environmental testing – Part 2: Tests – Test Fc: Vibration (sinusoidal)

IEC 60068-2-7:1983, Environmental testing – Part 2: Tests – Test Ga: Acceleration, steady state

IEC 60068-2-13:1983, Environmental testing – Part 2: Tests – Test M: Low air pressure

IEC 60068-2-14:1984, Environmental testing – Part 2: Tests – Test N: Change of temperature

IEC 60068-2-20:1979, Environmental testing – Part 2: Tests – Test T: Soldering

IEC 60068-2-21:1999, Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices

IEC 60068-2-27:1987, Environmental testing – Part 2: Tests – Test Ea and guidance: Shock

IEC 60068-2-29:1987, Environmental testing – Part 2: Tests – Test Eb and guidance: Bump

IEC 60068-2-30:1980, Environmental testing – Part 2: Tests – Test Db and guidance: Damp heat, cyclic (12 + 12 hour cycle)

IEC 60068-2-58:1999, Environmental testing – Part 2-58: Tests – Tests Td: Test methods for solderability, resistance to dissolution of metalization and to soldering heat of surface mounting devices (SMD)

IEC 60068-2-78:2001, Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state

IEC 60617 (all parts) [DB]<sup>1</sup>, Graphical symbols for diagrams

QC 001001:2000, IEC Quality Assessment System for Electronic Components (IECQ) – Basic Rules

QC 001002-2:1998, IEC Quality Assessment System for Electronic Components (IECQ) – Rules of Procedure – Part 2: Documentation

QC 001002-3:1998, IEC Quality Assessment System for Electronic Components (IECQ) – Rules of Procedure – Part 3: Approval Procedures

QC 001005:2000, Register of Firms, Products and Services approved under the IECQ System, including ISO 9000

ISO 1000:1992, SI units and recommendation for the use of their multiples and of certain other units

## 1.3 Order of precedence

Where any discrepancies occur for any reason, documents shall rank in the following order of authority:

- detail specification;
- sectional specification;

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- any other international documents (for example, of the IEC) to which reference is made.

The same order of precedence shall apply to equivalent national documents.

# 2 Terminology and general requirements

## 2.1 General

Units, graphical symbols, letter symbols and terminology shall whenever possible, be taken from IEC 60617, IEC 60027, IEC 60050(561) and ISO 1000.

Any other units, symbols and terminology peculiar to one of the components covered by the Generic Specification, shall be taken from the relevant IEC or ISO documents listed under 1.2.

## 2.2 Terms and definitions

For the purposes of this part of IEC 61337, the following terms and definitions apply.

Further detailed information may be provided in IEC 61994-1 for some of the following terms.

<sup>&</sup>lt;sup>1</sup> "DB" refers to the IEC on-line database.

# 2.2.1

#### dielectric filter

filter in which one or more dielectric resonators are incorporated

#### 2.2.2

#### dielectric mono-block filter

filter consisting of a metallized rectangular ceramic block with cylindrical holes, which functions as a TEM (Transverse-ElectroMagnetic) mode filter with two or more stages

#### 2.2.3

# stripline filter

filter consisting of stripline resonators, which functions as a TEM mode filter with two or more stages

#### 2.2.4

#### microstripline filter

filter consisting of microstripline resonators, which functions as a TEM mode filter with two or more stages

#### 2.2.5

#### coplanar filter

filter consisting of coplanar line resonators, which functions as a TEM mode filter with two or more stages

#### 2.2.6

#### coupling factor

k

coupling factor of a band-pass filter is the degree of coupling between two resonators.

NOTE The coupling between dielectric resonators is mainly done either magnetically or electrically. According to each case, the equivalent circuit of coupling is expressed by inductive or capacitive coupling, respectively, see Figure 1.

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Figure 1 – Equivalent circuit

The coupling factor by inductive or capacitive coupling is defined by the following respective equations:

$$k = \frac{M}{\sqrt{L_1 \times L_2}} \qquad \qquad k = \frac{C_m}{\sqrt{C_1 \times C_2}}$$

where

 $L_1$ ,  $C_1$  and  $L_2$ ,  $C_2$  are the resonance circuit elements;

*M* is the mutual inductance;

- $C_m$  is the coupling capacitance;
- k is the coupling factor.

In the case of a symmetrical circuit of coupling, the coupling factor can be obtained from two resonance frequencies calculated or measured for the coupled resonators:

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$$k = \frac{\left|f_o^2 - f_e^2\right|}{f_o^2 + f_e^2}$$

where

- is the resonance frequency in the case of even mode excitation (open-circuited  $f_e$ symmetric plane);
- is the resonance frequency in the case of odd mode excitation (short-circuited fo symmetric plane).

The coupling factor of a band-stop filter is the degree of coupling between the resonator and the transmission line. The coupling factor k is defined as the ratio of the external power loss  $(P_e)$  of the resonator system to the internal power loss  $(P_u)$  of the resonator and can be expressed by a function of quality factor as follows:

$$k = \frac{P_e}{P_u} = \frac{Q_u}{Q_e} = \frac{Q_u}{Q_L} - 1$$

where

- is the unloaded quality factor of resonator; ndards  $Q_{\mu}$
- is the external quality factor of resonator;  $Q_{e}$
- is the loaded quality factor of resonator.  $Q_L$

#### 2.2.7

#### mid-band frequency

arithmetic mean of the cut-off frequencies (see Figures 2 and 3)

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#### cut-off frequency

frequency of the pass band at which the relative attenuation reaches a specified value (see Figures 2 and 3)

#### 2.2.9

# trap frequency

frequency of the trap at which the attenuation reaches a large peak value (see Figure 2)

#### 2.2.10

#### pass-band

band of frequencies in which the relative attenuation is equal to or less than a specified value (see Figures 2 and 3)

#### 2.2.11

#### pass bandwidth

separation of the frequencies between which the attenuation is equal to or less than a specified value (see Figure 2)

#### 2.2.12

#### stop band

band of frequencies in which the relative attenuation is equal to or greater than a specified value (see Figures 2 and 3)